SDAS017C - DECEMBER 1982 - REVISED JANUARY 1995

- High Capacitive-Drive Capability
- 'ALS832A Has Typical Delay Time of 4.8 ns (C_L = 50 pF) and Typical Power Dissipation of 4.5 mW Per Gate
- 'AS832B Has Typical Delay Time of 3.2 ns (C_L = 50 pF) and Typical Power Dissipation of Less Than 13 mW Per Gate
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

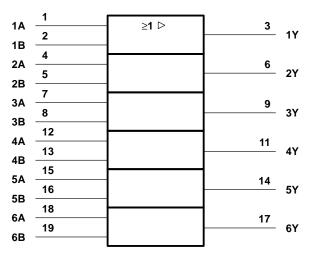
These devices contain six independent 2-input OR drivers. They perform the Boolean functions Y = A + B or $Y = \overline{A \cdot B}$ in positive logic.

The SN54ALS832A and SN54AS832B are characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ALS832A and SN74AS832B are characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each driver)

INP	JTS	OUTPUT
Α	В	Y
н	Х	Н
х	Н	н
L	L	L

logic symbol[†]



⁺ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

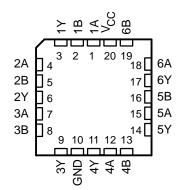
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



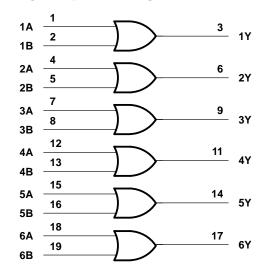
SN54ALS832A, SN54AS832B J PACKAGE
SN74ALS832A, SN74AS832B DW OR N PACKAGE
(TOP VIEW)

```		,	
1A [ 1B [ 1Y [ 2A [ 2B [ 2Y [ 3A [ 3B [ 3Y [ GND [	1 2 3 4 5 6 7 8 9 10	16 15 14 13	] V _{CC} ] 6B ] 6A ] 5B ] 5A ] 5Y ] 4B ] 4A ] 4Y

## SN54ALS832A, SN54AS832B . . . FK PACKAGE (TOP VIEW)



### logic diagram (positive logic)



Copyright © 1995, Texas Instruments Incorporated

SDAS017C - DECEMBER 1982 - REVISED JANUARY 1995

#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V _{CC} Input voltage, V _I	
Operating free-air temperature range, TA: SN54ALS832A	
Storage temperature range	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

		SN54ALS832A			SN7	UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.7			0.8	V
IOH	High-level output current			-12			-15	mA
IOL	Low-level output current			12			24	mA
TA	Operating free-air temperature	-55		125	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST		SN5	4ALS83	2A	SN7	2A		
PARAMETER	TEST CO	ST CONDITIONS		түр‡	MAX	MIN	түр‡	MAX	UNIT
VIK	$V_{CC} = 4.5 V,$	lj = -18 mA			-1.5			-1.5	V
	$V_{CC}$ = 4.5 V to 5.5 V,	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2			V _{CC} -2			
VOH		$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2		V
∨ОН	$V_{CC} = 4.5 V$	$I_{OH} = -12 \text{ mA}$	2						v
		I _{OH} = -15 mA				2			
Ve	V _{CC} = 4.5 V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	0.4 V
VOL	VCC = 4.3 V	I _{OL} = 24 mA					0.35	0.5	v
lj	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA
ΙIH	$V_{CC} = 5.5 V,$	V _I = 2.7 V			20			20	μA
١	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.1			-0.1	mA
١O§	V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
ІССН	V _{CC} = 5.5 V,	V _I = 4.5 V		6	9		6	9	mA
ICCL	V _{CC} = 5.5 V,	V _I = 0		9.5	16		9.5	16	mA

[‡] All typical values are at V_{CC} = 5 V, T_A = 25°C.

\$ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.



SDAS017C - DECEMBER 1982 - REVISED JANUARY 1995

#### switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	ТО (OUTPUT)	Ci Ri	V _{CC} = 4.5 V to 5.5 V, C _L = 50 pF, R _L = 500 Ω, T _A = MIN to MAX [†]		<b>F</b> , Ω,			
			SN54ALS832A		SN74ALS832A		832A SN74ALS832A		
			MIN	MAX	MIN	MAX			
^t PLH	A or B	V	1	13	2	9			
^t PHL	A OF B	Ŷ	1	11	1	8	ns		

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage, V _{CC}	
Operating free-air temperature range, T _A : SN54AS832B	–55°C to 125°C
SN74AS832B	0°C to 70°C
Storage temperature range	-65°C to 150°C

Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions§

		SN54AS832B		2B	SN74AS832B			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
ЮН	High-level output current			-40			-48	mA
IOL	Low-level output current			40			48	mA
TA	Operating free-air temperature	-55		125	0		70	°C

§ These high sink- or source-current devices are not recommended for use above 40 MHz.



SDAS017C - DECEMBER 1982 - REVISED JANUARY 1995

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN	SN54AS832B			SN74AS832B			
PARAMETER	TEST CC	JNDHIONS	MIN	TYP†	MAX	MIN	TYP†	MAX	UNIT	
VIK	V _{CC} = 4.5 V,	lj = -18 mA			-1.2			-1.2	V	
	$V_{CC}$ = 4.5 V to 5.5 V,	$I_{OH} = -2 \text{ mA}$	V _{CC} -2			V _{CC} -2				
Ver		$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2		V	
VOH	V _{CC} = 4.5 V	$I_{OH} = -40 \text{ mA}$	2						v	
		$I_{OH} = -48 \text{ mA}$				2				
VOL	VCC = 4.5 V	I _{OL} = 40 mA		0.25	0.5				V	
VOL	VCC = 4.5 V	I _{OL} = 48 mA					0.35	0.5	v	
lj	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA	
Ιн	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μA	
١ _{IL}	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.5			-0.5	mA	
IO‡	$V_{CC} = 5.5 V,$	V _O = 2.25 V	-50		-200	-50		-200	mA	
ICCH	V _{CC} = 5.5 V,	V _I = 4.5 V		11	17		11	17	mA	
ICCL	V _{CC} = 5.5 V,	V <b>I</b> = 0		22	36		22	36	mA	

[†] All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

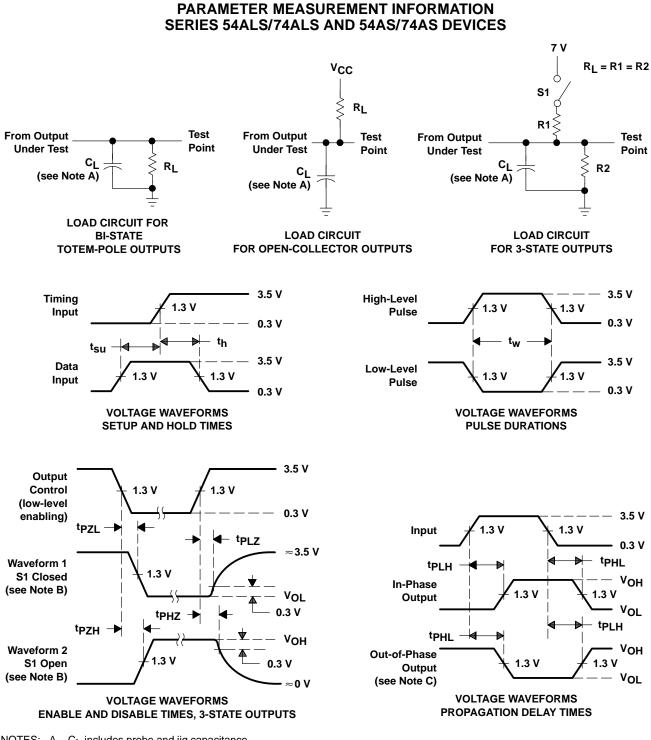
#### switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	CL RL TA	V _{CC} = 4.5 V to C _L = 50 pF, R _L = 500 Ω, T _A = MIN to M/ SN54AS832B SN		9		
			MIN	MAX	MIN	MAX		
^t PLH	A or B	Y -	1	7.5	1	6.3	ns	
^t PHL	AUB		1	7	1	6.3	115	

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



SDAS017C - DECEMBER 1982 - REVISED JANUARY 1995



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR  $\leq$  1 MHz, t_f = t_f = 2 ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.
  - ne oupus are measured one at a time with one transition per measurement.

#### Figure 1. Load Circuits and Voltage Waveforms



#### **IMPORTANT NOTICE**

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

Copyright © 1996, Texas Instruments Incorporated